

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s):	Mehrdad Nikoonahad		
Title:	Optical System for Measuring Samples Using Short Wavelength Radiation		
Application No.:	10/718,126	Filing Date:	November 19, 2003
Examiner:	Pham, Hoa Q.	Group Art Unit:	2886
Docket No.:	TNCR.197US1	Conf. No.:	9108

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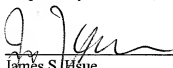
COMMENTS ON STATEMENT OF REASONS FOR ALLOWANCE

Dear Sir:

We disagree with the Examiner's statement of reasons for allowance as we feel the statement does not pertain to claims 125, 128 and 146.

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Respectfully submitted,



James S. Hsue
Reg. No. 29,545

March 18, 2008

Date

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